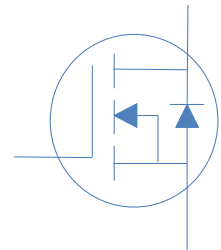
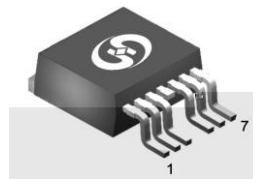


65V N-Ch Power MOSFET

V_{DS}	65	V
$R_{DS(on),typ}$	1.35	m
I_D (Silicon Limited)	363	A
I_D (Package Limited)	180	A



Part Number	Package	Marking
HGB016NE6A	TO-263-7	GB016NE6A

Absolute Maximum Ratings at $T_j=25^{\circ}\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	$T_C=25^{\circ}\text{C}$	363	A
		$T_C=100^{\circ}\text{C}$	257	
		$T_C=25^{\circ}\text{C}$	180	
Continuous Drain Current (Silicon Limited)			180	
Drain to Source Voltage	V_{DS}	-	65	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	900	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.1\text{mH}, T_C=25^{\circ}\text{C}$	180	mJ
Power Dissipation	P_D	$T_C=25^{\circ}\text{C}$	333	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 175	$^{\circ}\text{C}$

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Ambient	R_{JA}	60	$^{\circ}\text{C/W}$
Thermal Resistance Junction-Case	R_{JC}	0.45	$^{\circ}\text{C/W}$



- 8671 -
- 3042 - pF
161 -

28 -

$V_{GS}=0V, I_F=20A$

- 0.9

Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

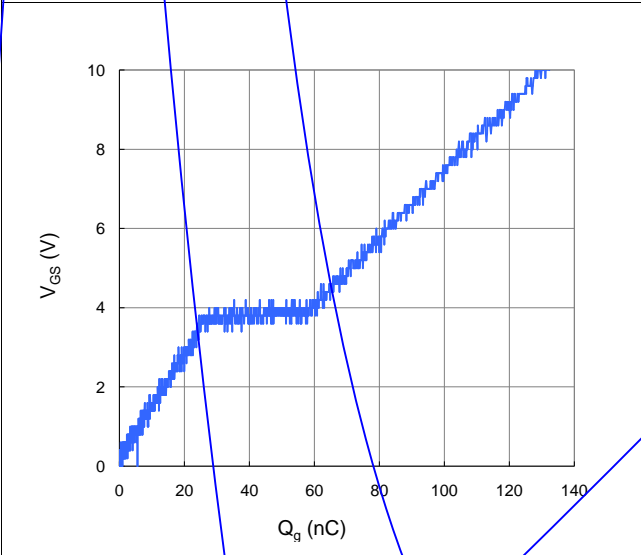


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

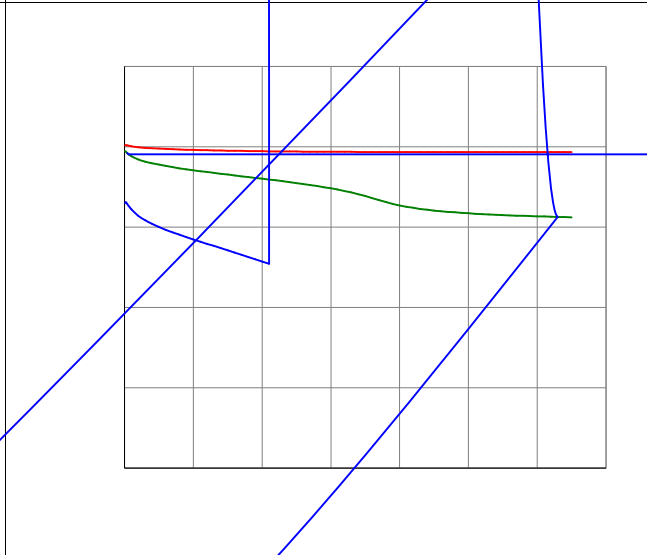


Figure 9. Maximum Safe Operating Area

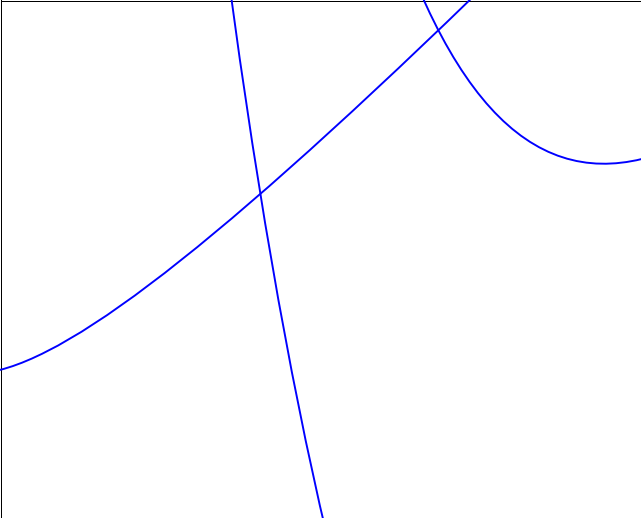


Figure 10. Maximum Drain Current vs. Case Temperature

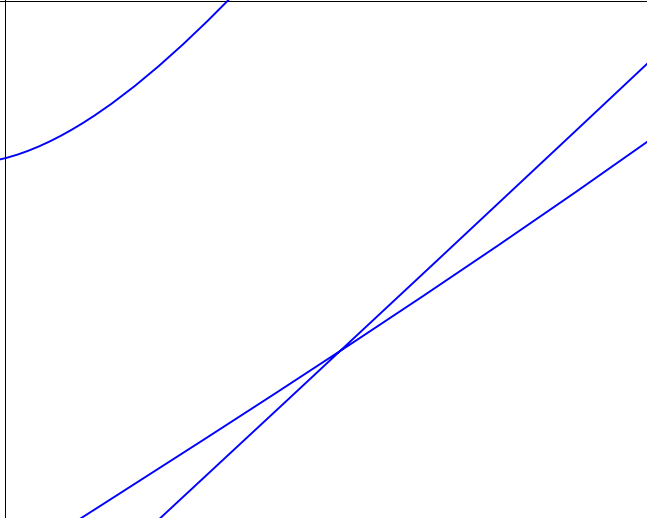
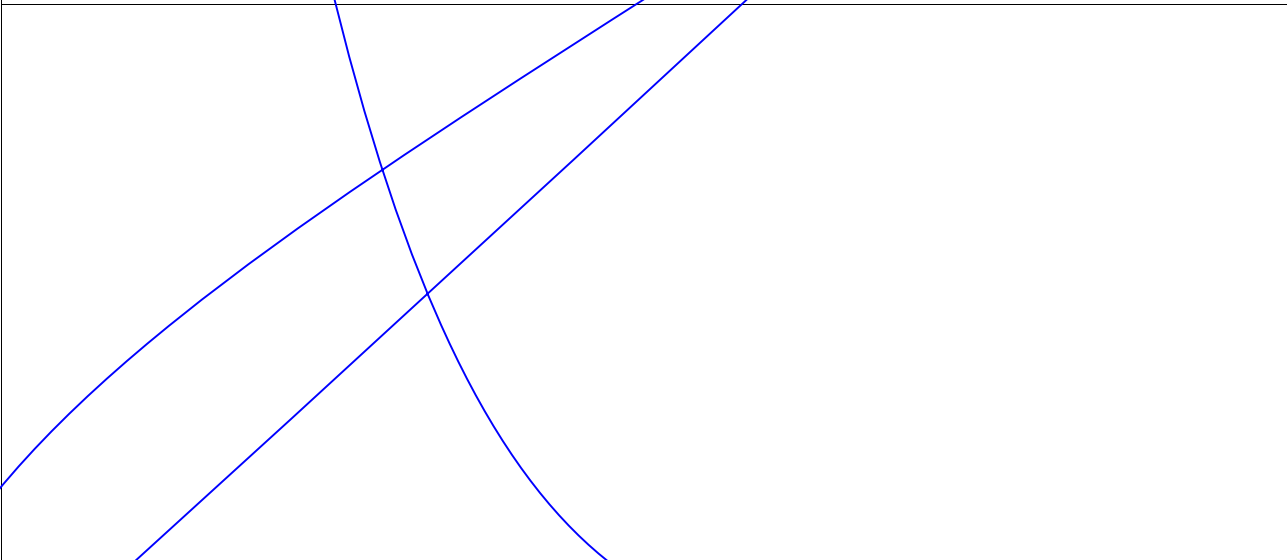
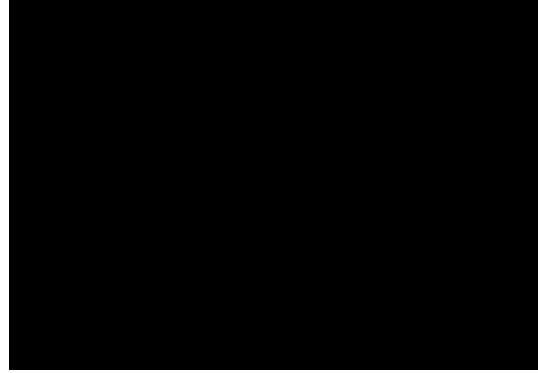
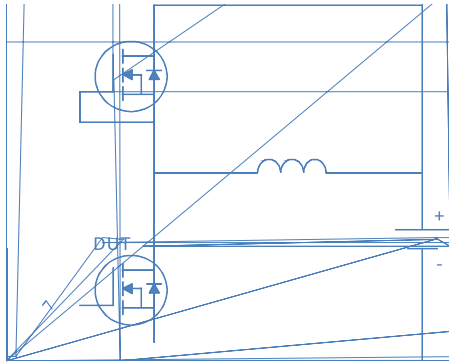


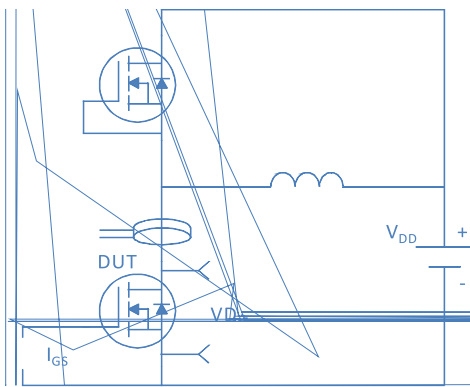
Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient



Inductive switching Test



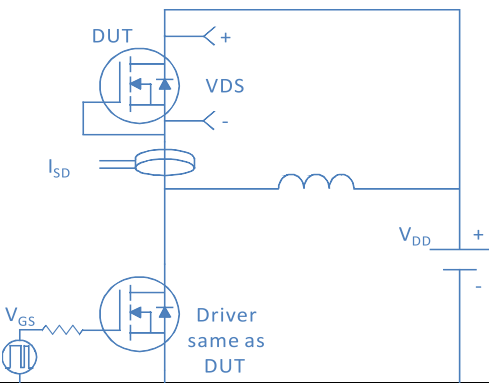
Gate Charge Test



Uclamped Inductive Switching (UIS) Test

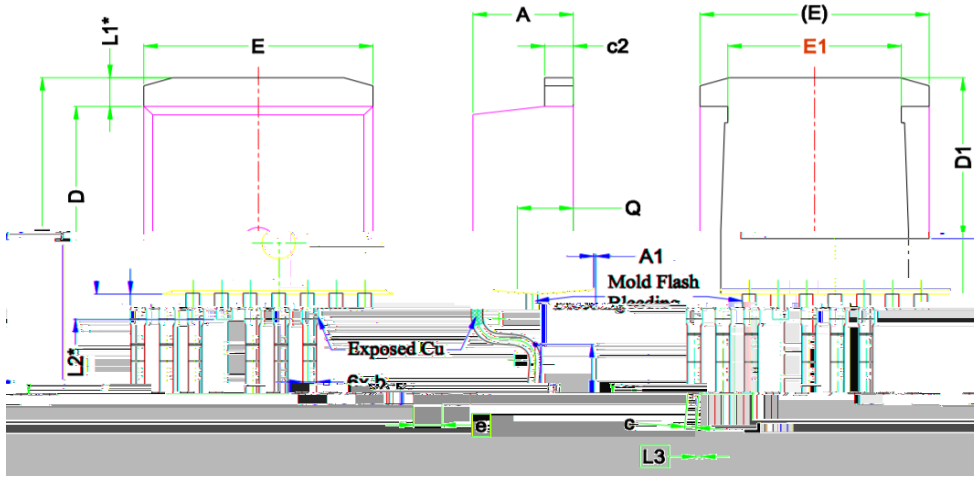


Diode Recovery Test



Package Outline

TO-263-7, 7 leads



		DIMENSIONS	
NOM.	MAX.	MIN.	MIN.
4.44	4.84	4.24	
0.70		0.50	0.50
0.50		0.40	0.50
1.40		1.27	
8.92		8.92	
		7.65	
10.30		10.43	
7.89		6.89	7.77
		1.27 BSC	
15.86		14.81	15.00
2.79		1.53	2.32
		1.33 REF	
		1.20 REF	
		0.25 REF	